

# Quad 2-input NAND gate

# 74F00

## FEATURE

- Industrial temperature range available (-40°C to +85°C)

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F00	3.4ns	4.4mA

## ORDERING INFORMATION

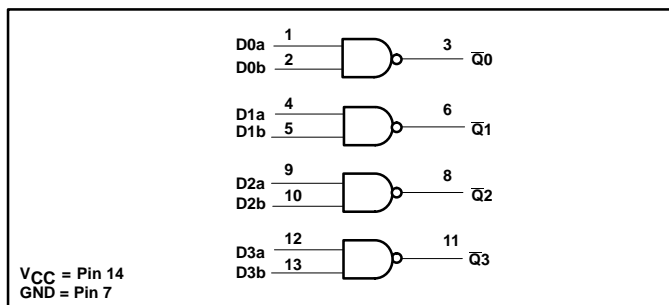
DESCRIPTION	ORDER CODE	
	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$ , $T_{amb} = 0^{\circ}C$ to $+70^{\circ}C$	INDUSTRIAL RANGE $V_{CC} = 5V \pm 10\%$ , $T_{amb} = -40^{\circ}C$ to $+85^{\circ}C$
14-pin plastic DIP	N74F00N	I74F00N
14-pin plastic SO	N74F00D	I74F00D

## INPUT AND OUTPUT LOADNG AND FAN OUT TABLE

PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
Dna, Dnb	Data inputs	1.0/1.0	20µA/0.6mA
$\bar{Q}n$	Data output	50/33	1.0mA/20mA

NOTE: One (1.0) FAST unit load is defined as: 20µA in the high state and 0.6mA in the low state.

## LOGIC DIAGRAM



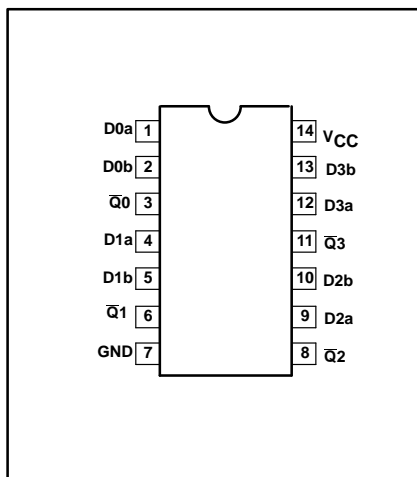
## FUNCTION TABLE

INPUTS		OUTPUT
Dna	Dnb	$\bar{Q}n$
L	L	H
L	H	H
H	L	H
H	H	L

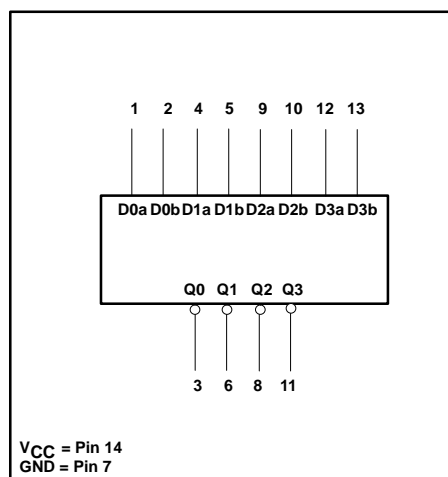
### NOTES:

- H = High voltage level
- L = Low voltage level

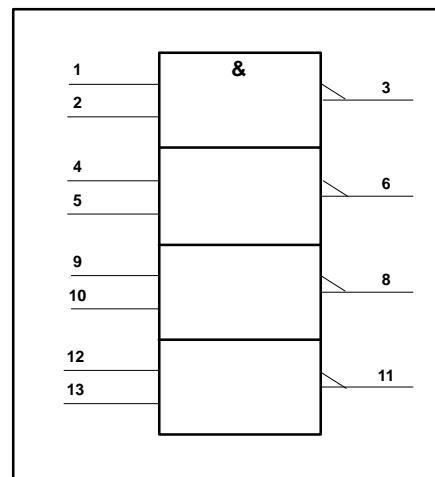
## PIN CONFIGURATION



## LOGIC SYMBOL



## IEC/IEEE SYMBOL



## Quad 2-input NAND gate

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**ABSOLUTE MAXIMUM RATINGS**

(Operation beyond the limit set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free air temperature range.)

SYMBOL	PARAMETER		RATING	UNIT
V <sub>CC</sub>	Supply voltage		-0.5 to +7.0	V
V <sub>IN</sub>	Input voltage		-0.5 to +7.0	V
I <sub>IN</sub>	Input current		-30 to +5	mA
V <sub>OUT</sub>	Voltage applied to output in high output state		-0.5 to V <sub>CC</sub>	V
I <sub>OUT</sub>	Current applied to output in low output state		40	mA
T <sub>amb</sub>	Operating free air temperature range	Commercial range	0 to +70	°C
		Industrial range	-40 to +85	°C
T <sub>stg</sub>	Storage temperature range		-65 to +150	°C

**RECOMMENDED OPERATING CONDITIONS**

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN	NOM	MAX	
V <sub>CC</sub>	Supply voltage	4.5	5.0	5.5	V
V <sub>IH</sub>	High-level input voltage	2.0			V
V <sub>IL</sub>	Low-level input voltage			0.8	V
I <sub>Ik</sub>	Input clamp current			-18	mA
I <sub>OH</sub>	High-level output current			-1	mA
I <sub>OL</sub>	Low-level output current			20	mA
T <sub>amb</sub>	Operating free air temperature range	Commercial range	0	+70	°C
		Industrial range	-40	+85	°C

**DC ELECTRICAL CHARACTERISTICS**

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS <sup>1</sup>	LIMITS			UNIT	
			MIN	TYP <sup>2</sup>	MAX		
V <sub>OH</sub>	High-level output voltage	V <sub>CC</sub> = MIN, V <sub>IL</sub> = MAX	±10%V <sub>CC</sub>	2.5		V	
		V <sub>IH</sub> = MIN, I <sub>OH</sub> = MAX	±5%V <sub>CC</sub>	2.7	3.4	V	
V <sub>OL</sub>	Low-level output voltage	V <sub>CC</sub> = MIN, V <sub>IL</sub> = MAX	±10%V <sub>CC</sub>		0.30	0.50	V
		V <sub>IH</sub> = MIN, I <sub>OL</sub> = MAX	±5%V <sub>CC</sub>		0.30	0.50	V
V <sub>IK</sub>	Input clamp voltage	V <sub>CC</sub> = MIN, I <sub>I</sub> = I <sub>IK</sub>			-0.73	-1.2	V
I <sub>I</sub>	Input current at maximum input voltage	V <sub>CC</sub> = MAX, V <sub>I</sub> = 7.0V				100	μA
I <sub>IH</sub>	High-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.7V				20	μA
I <sub>IL</sub>	Low-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.5V				-0.6	mA
I <sub>OS</sub>	Short-circuit output current <sup>3</sup>	V <sub>CC</sub> = MAX		-60		-150	mA
I <sub>CC</sub>	Supply current (total)	I <sub>CCH</sub> V <sub>CC</sub> = MAX	V <sub>IN</sub> = GND		1.9	2.8	mA
		I <sub>CCL</sub> V <sub>CC</sub> = MAX	V <sub>IN</sub> = 4.5V		6.8	10.2	mA

**NOTES:**

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at V<sub>CC</sub> = 5V, T<sub>amb</sub> = 25°C.
- Not more than one output should be shorted at a time. For testing I<sub>OS</sub>, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I<sub>OS</sub> tests should be performed last.

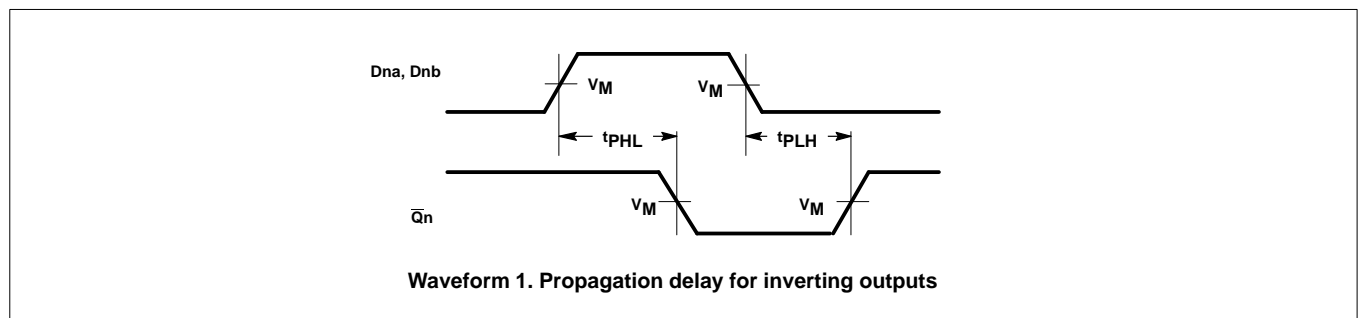
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## AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS						UNIT	
			$T_{amb} = +25^{\circ}\text{C}$			$T_{amb} = 0^{\circ}\text{C to } +70^{\circ}\text{C}$		$T_{amb} = -40^{\circ}\text{C to } +85^{\circ}\text{C}$		
			$V_{CC} = +5.0\text{V}$ $C_L = 50\text{pF}$ $R_L = 500\Omega$			$V_{CC} = +5.0\text{V} \pm 10\%$ $C_L = 50\text{pF}$ $R_L = 500\Omega$		$V_{CC} = +5.0\text{V} \pm 10\%$ $C_L = 50\text{pF}$ $R_L = 500\Omega$		
			MIN	TYP	MAX	MIN	MAX	MIN		MAX
$t_{PLH}$ $t_{PHL}$	Propagation delay Dna, Dnb to $\bar{Q}_n$	Waveform 1	2.4 2.0	3.7 3.2	5.0 4.3	2.4 2.0	6.0 5.3	2.0 1.5	6.5 6.0	ns

## AC WAVEFORMS



**Note:** For all waveforms,  $V_M = 1.5\text{V}$ .

## TEST CIRCUIT AND WAVEFORM

**Test circuit for totem-pole outputs**

**DEFINITIONS:**  
 $R_L$  = Load resistor; see AC electrical characteristics for value.  
 $C_L$  = Load capacitance includes jig and probe capacitance; see AC electrical characteristics for value.  
 $R_T$  = Termination resistance should be equal to  $Z_{OUT}$  of pulse generators.

**Input pulse definition**

family	INPUT PULSE REQUIREMENTS					
	amplitude	$V_M$	rep. rate	$t_w$	$t_{TLH}$	$t_{THL}$
74F	3.0V	1.5V	1MHz	500ns	2.5ns	2.5ns